

Search Notes

Application/Control No.

10/634,269

Examiner

Mark Blouin

Applicant(s)/Patent under
Reexamination

YAO ET AL.

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR